

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/010,807 | Applicant(s)/Patent Under Reexamination TAN ET AL. | |
| | Examiner Christopher L. Chin | Art Unit 1641 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------------|----------------|
| | A | US-4,054,465 | 10-1977 | Ziobrowski, Bernard George | 106/434 |
| | B | US-4,438,156 | 03-1984 | Homola et al. | 427/474 |
| | C | US-5,091,206 | 02-1992 | Wang et al. | 427/2.18 |
| | D | US-5,667,716 | 09-1997 | Ziolo et al. | 252/62.52 |
| | E | US-5,695,901 | 12-1997 | Selim, Sami | 430/106.2 |
| | F | US-5,874,111 | 02-1999 | Maitra et al. | 424/499 |
| | G | US-5,879,715 | 03-1999 | Higgins et al. | 424/489 |
| | H | US-5,958,329 | 09-1999 | Brown, Donald Lee | 266/176 |
| | I | US-6,103,379 | 08-2000 | Margel et al. | 428/403 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.